

Preliminary

SIDC01D120H6

Fast switching diode chip in EMCON-Technology

FEATURES:

- 1200V EMCON technology 120 µm chip
- soft, fast switching
- low reverse recovery charge
- small temperature coefficient

This chip is used for:

EUPEC power modules and discrete devices



Applications:

SMPS, resonant applications, drives

| Chip Type | V_R | I _F | Die Size | Package | Ordering Code |
|--------------|-------|----------------|---------------------------|--------------|-----------------------|
| SIDC01D120H6 | 1200V | 0.6A | 1.2 x 1.1 mm ² | sawn on foil | Q67050-A4171- A001 |

MECHANICAL PARAMETER:

| Raster size | 1.2 x 1.1 | | | | |
|---------------------------------|-------------------------------------------------------------------------------------------|-----------------|--|--|--|
| Area total / active | 1.32 / 0.25 | mm ² | | | |
| Anode pad size | 0.48 x 0.38 | | | | |
| Thickness | 120 | μm | | | |
| Wafer size | 150 | mm | | | |
| Flat position | 180 | deg | | | |
| Max. possible chips per wafer | 11812 pcs | | | | |
| Passivation frontside | Photoimide | | | | |
| Anode metallisation | 3200 nm AlSiCu | | | | |
| Cathode metallisation | 1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding | | | | |
| Die bond | electrically conductive glue or solder | | | | |
| Wire bond | AI, ≤ 250μm | | | | |
| Reject Ink Dot Size | Ø 0.3 mm | | | | |
| Recommended Storage Environment | store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C | | | | |



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Maximum Ratings

| Parameter | Symbol | Condition | Value | Unit |
|---------------------------------------------------------------------|----------------------------|----------------------------------|---------|------|
| Repetitive peak reverse voltage | V_{RRM} | | 1200 | ٧ |
| Continuous forward current limited by T_{jmax} | I _F | | 0.6 | |
| Single pulse forward current (depending on wire bond configuration) | I _{FSM} | $t_P = 10 \text{ ms sinusoidal}$ | tbd | А |
| Maximum repetitive forward current limited by T_{jmax} | I _{FRM} | | 1.2 | |
| Operating junction and storage temperature | $T_{\rm j}$, $T_{ m stg}$ | | -55+150 | °C |

$\textbf{Static Electrical Characteristics} \text{ (tested on chip), } \textit{T}_{j}\text{=25 °C, unless otherwise specified}$

| Parameter | Symbol | Cond | Value | | | Unit | |
|---------------------------------|-----------------|-----------------------|----------------------------|------|------|------|----|
| raiailietei | Syllibol | Conditions | | min. | Тур. | max. | |
| Reverse leakage current | I_{R} | V _R =1200V | <i>T_j</i> =25°C | | | 27 | μΑ |
| Cathode-Anode breakdown Voltage | V _{Br} | $I_R = mA$ | <i>T_j</i> =25°C | 1200 | | | V |
| Forward voltage drop | V _F | I _F =0.6A | <i>T_j</i> =25°C | | 1.6 | | V |

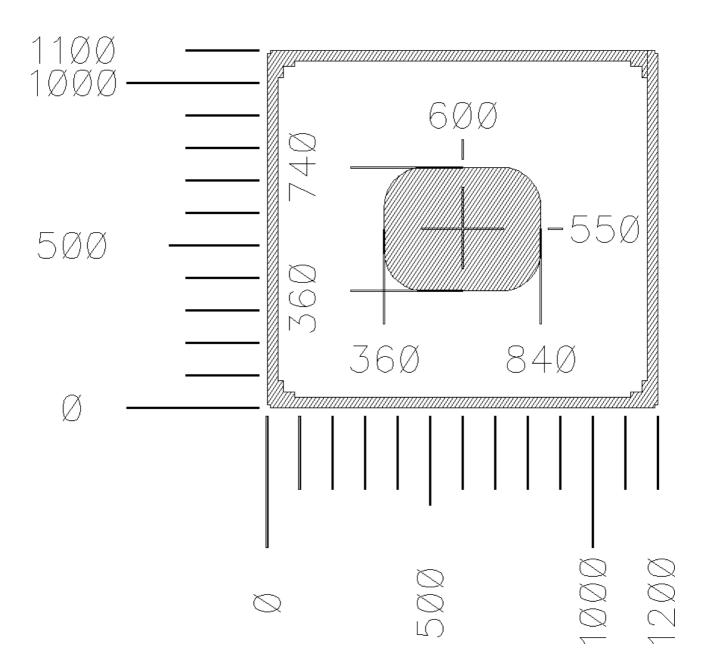
Dynamic Electrical Characteristics, at $T_j = 25$ °C, unless otherwise specified, tested at component

| Parameter | Symbol | Conditions | | Value | | | Unit |
|------------------------------|-----------------------|--------------------------------------------------|------------------------------------|-------|------|------|----------|
| raiailletei | Syllibol | | | min. | Тур. | max. | |
| Reverse recovery time | t _{rr1} | $I_F=0.6A$ | $T_j = 25$ °C | | tbd | | |
| | t_{rr2} | $di/dt=600A/ms$ $V_R=600V$ | $T_j = 125$ °C | | | | ns |
| Peak recovery current | I _{RRM1} | I _F =0.6A | $T_j = 25$ °C | | 1.5 | | A |
| | I _{RRM2} | $V_{R} = 600 \text{A/ms}$ $V_{R} = 600 \text{V}$ | $T_j = 125$ °C | | 2.5 | | |
| Reverse recovery charge | Q _{rr1} | I _F =0.6A | T _j =25°C | | 0.4 | | μC |
| | Q _{rr2} | | T _j =125°C | | 0.9 | | μΟ |
| Peak rate of fall of reverse | di _{rr1} /dt | I _F =0.6A | T _j =25°C | | tbd | | |
| recovery current | di _{rr2} /dt | di/dt=600A/ms $V_R=600V$ | T _j =125°C | | | | A/μs |
| Softness | S1 | I _F =0.6A di/dt=600A/ m s | <i>T_j</i> =25° <i>C</i> | | tbd | | 1 |
| | S2 | $V_R = 600V$ | $T_j=125^{\circ}C$ | | | | <u> </u> |



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CHIP DRAWING:





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FURTHER ELECTRICAL CHARACTERISTICS:

| This chip data sheet refers to the | INFINEON TECHNOLOGIES / | tbd |
|------------------------------------|-------------------------|-----|
| device data sheet | EUPEC | tba |

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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